

Features

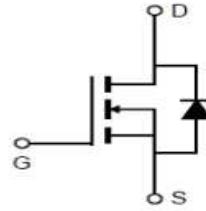
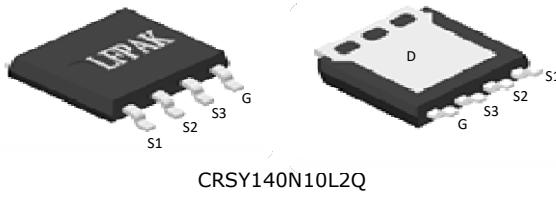
- Uses CRM(CQ) advanced SkyMOS2 technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Qualified according to AEC-Q101 standard

Product Summary

V_{DS}	100V
$R_{DS(on)}@10V$ typ	6.5mΩ
I_D	80A

Applications

- Motor control and drive
- Battery management
- UPS (Uninterruptible Power Supplies)

100% DVDS Tested**100% Avalanche Tested****Package Marking and Ordering Information**

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRSY140N10L2Q	140N10L2Q	LFPAK5*6	Tape&reel	N/A	N/A	4000pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	100	V
Continuous drain current	I_D		
$T_C = 25^\circ\text{C}$ (Silicon limit)		80	A
$T_C = 100^\circ\text{C}$ (Silicon limit)		56	
Pulsed drain current ($T_C = 25^\circ\text{C}$, t_p limited by T_{jmax})	$I_{D\text{ pulse}}$	316	A
Avalanche energy, single pulse ($I_{AS} = 30\text{A}$, $R_g=25\Omega$) ^[1]	E_{AS}	135	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation ($T_C = 25^\circ\text{C}$)	P_{tot}	97	W
Operating junction and storage temperature	T_j, T_{stg}	-55...+175	°C
Soldering temperature, wave soldering only allowed at leads (1.6mm from case for 10s)	T_{sold}	260	°C

Notes: 1. EAS was tested at $T_j = 25^\circ\text{C}$, $L = 0.3\text{mH}$, $I_{AS} = 30\text{A}$, $V_{GS}=10\text{V}$.**Thermal Resistance**

Parameter	Symbol	Value	Unit
		min.	Max
Thermal resistance, junction - case.	R_{thJC}	-	1.55
Thermal resistance, junction - ambient(min. footprint)	R_{thJA}	-	56
Thermal resistance, junction - plastic case	R_{thj-pc}	-	21

Electrical Characteristic (at $T_j = 25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Static Characteristic						
Drain-source breakdown voltage	BV_{DSS}	100	-		V	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\text{uA}$
Gate threshold voltage	$\text{V}_{\text{GS}(\text{th})}$	1.2	-	2.2	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\text{uA}$
Zero gate voltage drain current	I_{DSS}	-	-	1	μA	$\text{V}_{\text{DS}}=100\text{V}, \text{V}_{\text{GS}}=0\text{V}$
		-	-	100		$\text{T}_j=25^\circ\text{C}$
Gate-source leakage current	I_{GSS}	-	-	± 100	nA	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$
Drain-source on-state resistance	$\text{R}_{\text{DS}(\text{on})}$	1 1	6.5 8.5	8.2 10.0	$\text{m}\Omega$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=40\text{A}$ $\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=32\text{A}$
Transconductance	g_{fs}	102	105	210	S	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_D=40\text{A}$

Dynamic Characteristic

Input Capacitance	C_{iss}	1600	2260	4100	pF	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=50\text{V}, \text{f}=1\text{MHz}$
Output Capacitance	C_{oss}	80	400	2000		
Reverse Transfer Capacitance	C_{rss}	2	15	90		
Gate Total Charge	Q_{G}	20	40	80	nC	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=50\text{V}, \text{I}_D=40\text{A}, \text{f}=1\text{MHz}$
Gate-Source charge	Q_{gs}	5	10	25		
Gate-Drain charge	Q_{gd}	3	6	12		
Turn-on delay time	$\text{t}_{\text{d}(\text{on})}$	6	12.5	25	ns	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DD}}=50\text{V}, \text{R}_{\text{G_ext}}=3.0\Omega$
Rise time	t_r	20	40	120		
Turn-off delay time	$\text{t}_{\text{d}(\text{off})}$	16	32	64		
Fall time	t_f	45	90	180		
Gate resistance	R_{G}	0.3	1.5	3	Ω	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=0\text{V}, \text{f}=1\text{MHz}$

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Diode continuous forward current	I_{s}	-	-	80	A	$\text{T}_c = 25^\circ\text{C}$
Diode pulse current	$\text{I}_{\text{s pulse}}$	-	-	320	A	$\text{T}_c = 25^\circ\text{C}$
Body Diode Forward Voltage	V_{SD}	0.4	0.9	1.4	V	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_{\text{SD}}=40\text{A}$
Body Diode Reverse Recovery Time	t_{rr}	52	105	210	ns	$\text{I}_{\text{F}}=40\text{A}, \text{dI}/\text{dt}=100\text{A}/\mu\text{s}$
Body Diode Reverse Recovery Charge	Q_{rr}	85	170	340	nC	

Typical Performance Characteristics

Fig 1: Output Characteristics

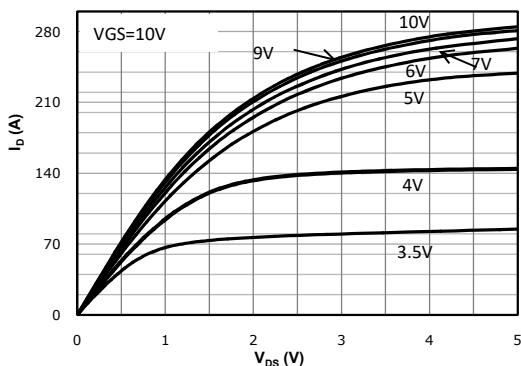


Fig 2: Transfer Characteristics

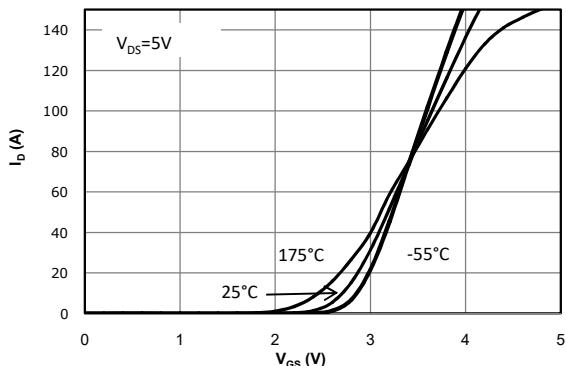
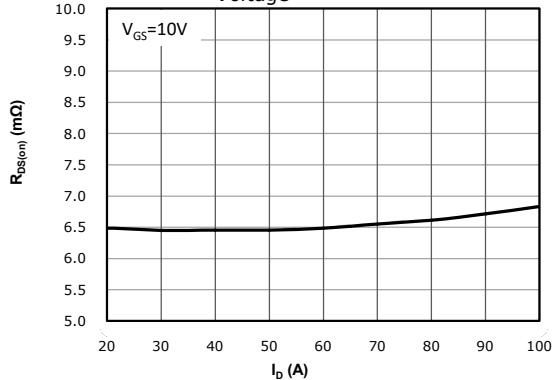
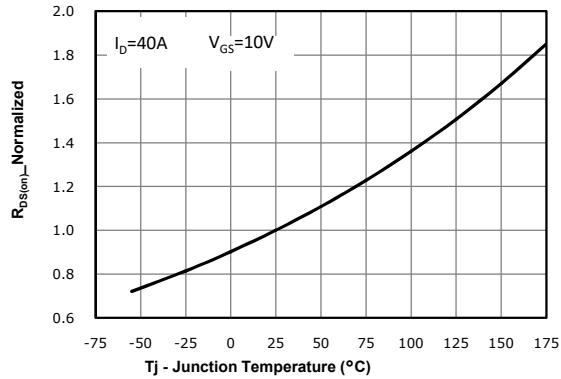
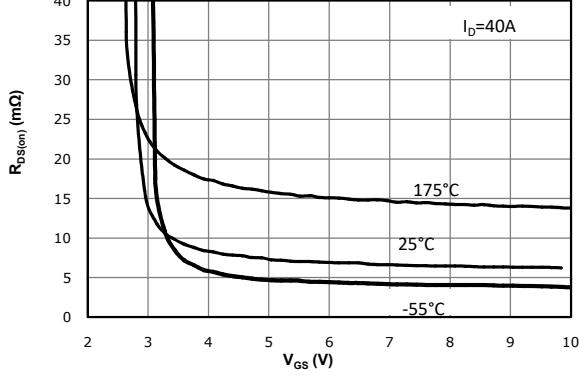
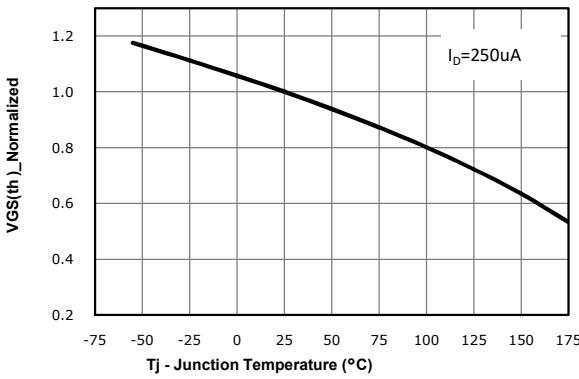
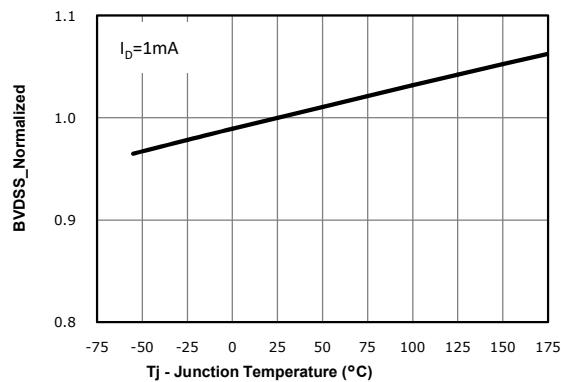
Fig 3: $R_{DS(on)}$ vs Drain Current and Gate VoltageFig 4: $R_{DS(on)}$ vs Gate VoltageFig 6: $V_{GS(th)}$ vs. TemperatureFig 7: BV_{DSS} vs. Temperature

Fig 8: Capacitance Characteristics

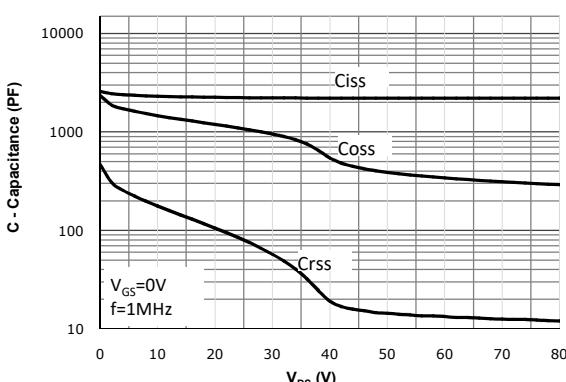


Fig 9: Gate Charge Characteristics

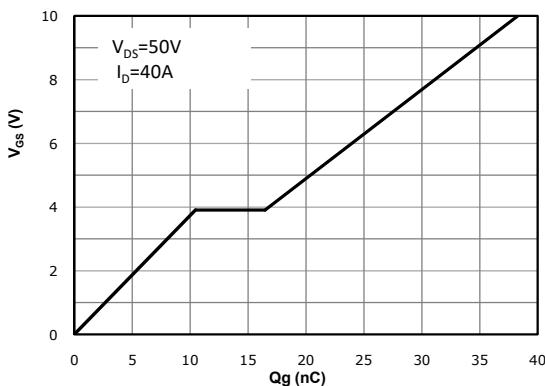


Fig 10: Body-diode Forward Characteristics

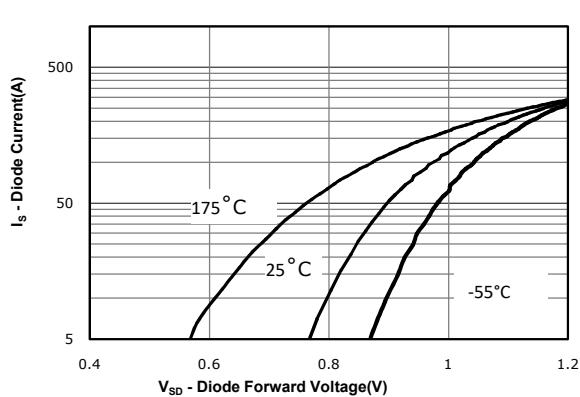


Fig 11: Power Dissipation

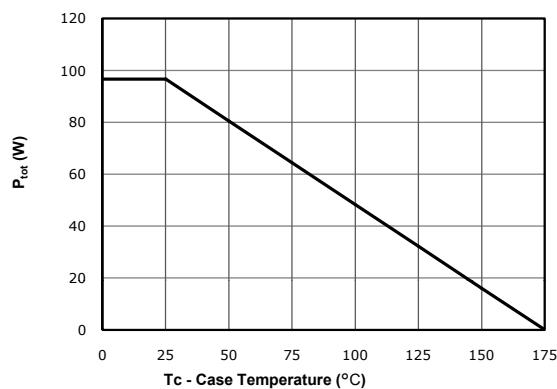


Fig 12: Drain Current Derating

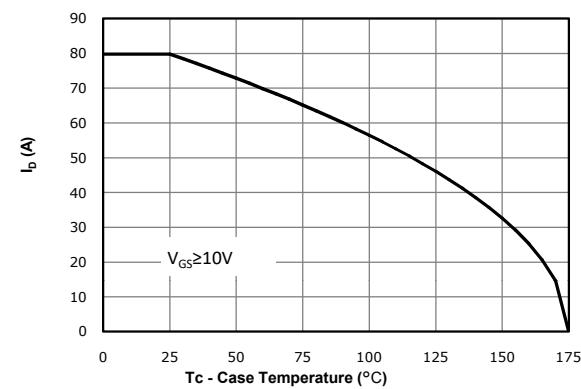


Fig 13: Safe Operating Area

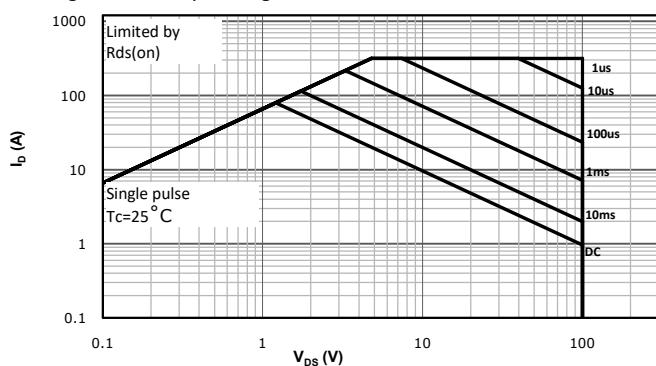
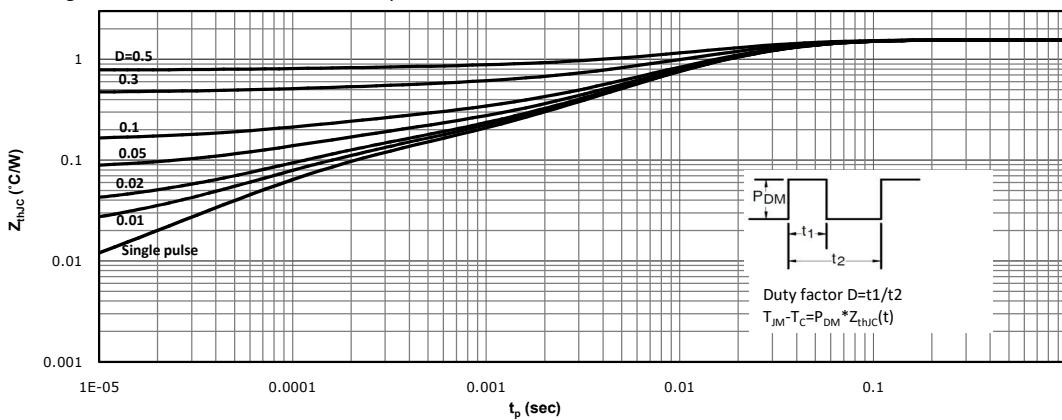
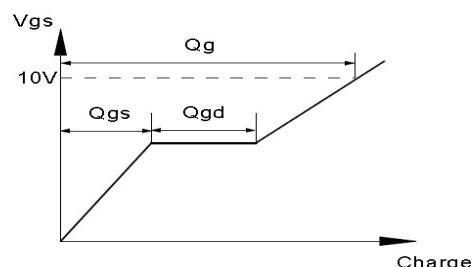
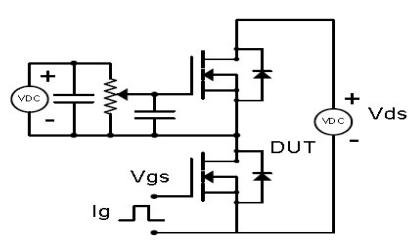


Fig 14: Max. Transient Thermal Impedance

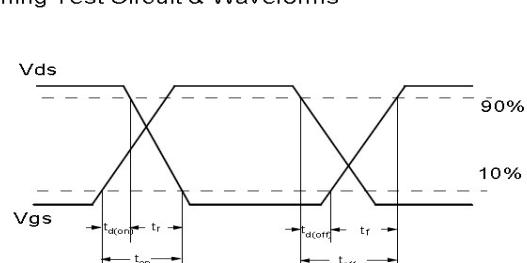
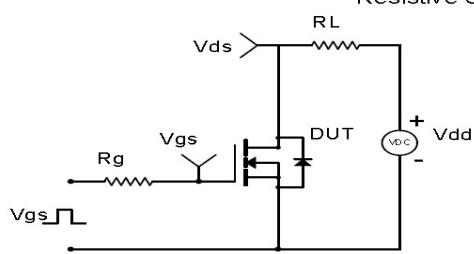


Test Circuit & Waveform

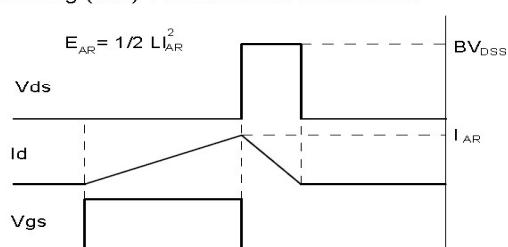
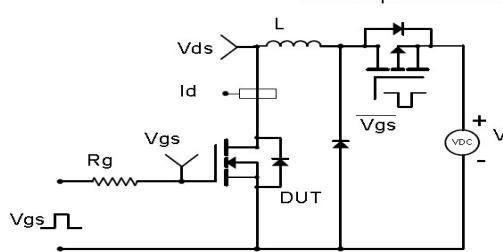
Gate Charge Test Circuit & Waveform



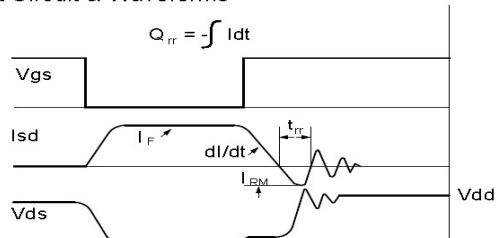
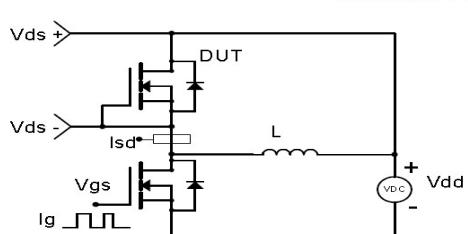
Resistive Switching Test Circuit & Waveforms

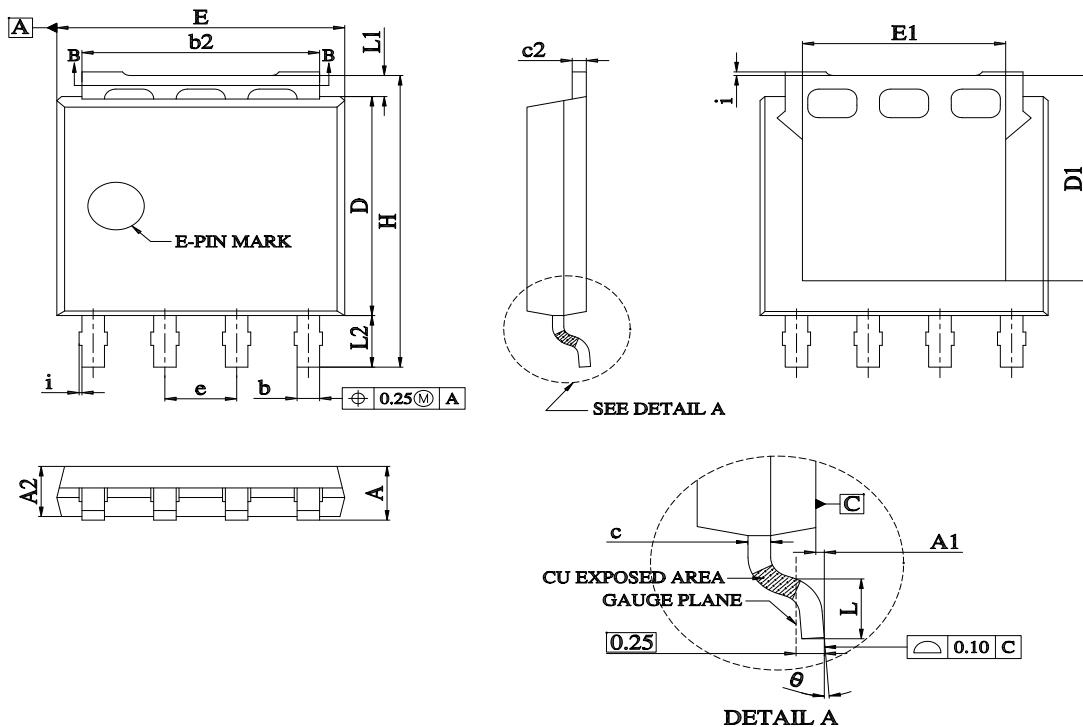


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



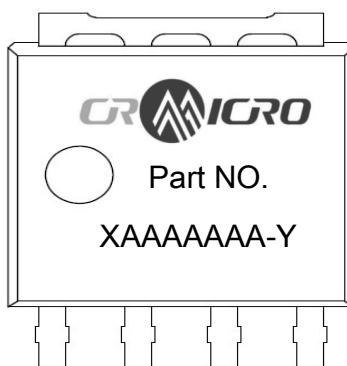
Diode Recovery Test Circuit & Waveforms



Package Outline: LFPAK5*6


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.00	1.20	0.039	0.047
A1	0.00	0.15	0.000	0.006
A2	0.95	1.15	0.037	0.045
b	0.32	0.50	0.013	0.020
b2	3.80	4.41	0.150	0.174
c	0.17	0.25	0.007	0.010
c2	0.22	0.30	0.009	0.012
D	4.45	4.70	0.175	0.185
D1	--	4.45	--	0.175
E	4.90	5.30	0.193	0.209
E1	3.45	3.75	0.136	0.148
e	1.27 BSC		0.050 BSC	
H	5.95	6.25	0.234	0.246
i	--	0.25	--	0.010
L	0.40	0.85	0.016	0.033
L1	0.27	0.57	0.011	0.022
L2	0.80	1.30	0.031	0.051
θ	0°	8°	0°	8°

Marking



NOTE:
XAAAAAAA-Y
X — Assembly location code
AAAAAAA — Assembly lot NO.last 7digits
Y — Bin code

Reversion History

Reversion	Date	Major changes
1.0	2022/12/20	Release of preliminary 1.0 version.
2.0	2024/3/14	Change Rthj- <u>pc</u> Max,Add Is /Is pulse.

Disclaimer

CRM reserves the right to change any product or information in this Specification at any time without prior notice.

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